

WHAT IS CLAIMED IS:

1. A method of inspecting an insulator to detect defects, said insulator having an aperture formed therein, the
5 method comprising:
 - placing said insulator inside a pressure-proof chamber, with a first electrode disposed within said aperture of said insulator and with a second electrode disposed at the exterior of said insulator,
 - 10 filling said pressure-proof chamber with air under a pressure which is higher than atmospheric pressure,
 - establishing a potential difference between said first electrode and second electrode, and measuring a level of leakage current which flows between said first and
15 second electrodes, and
 - judging whether said leakage current exceeds a predetermined value, to thereby judge whether or not said insulator is defective.
- 20 2. A method of insulator defect inspection applied to an insulator, said insulator having an aperture formed therein, the method comprising
 - disposing a first electrode within said aperture of said insulator with said insulator inserted into a cavity

formed in a second electrode, said second electrode being formed of metal plate,

establishing a potential difference between said first and second electrodes and measuring a level of leakage
5 current which flows between said first and second electrodes, and

judging whether there is a defect in said insulator, based upon whether or not said level of leakage current exceeds a predetermined value.

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3. A method of insulator defect inspection, said insulator having an aperture formed therein, the method comprising

disposing a first electrode within said aperture of
15 said insulator and disposing a second electrode such as to peripherally enclose said insulator,

establishing a potential difference between said first and second electrodes and measuring a level of leakage
current which flows between said first and second
20 electrodes, and

judging whether there is a defect in said insulator, based upon whether or not said level of leakage current exceeds a predetermined value.

4. A method of insulator defect inspection according to claim 1, wherein said insulator comprises a plurality of insulators having respective apertures formed therein and said first electrode comprises a plurality of first
5 electrodes corresponding to respective ones of said plurality of insulators, wherein said potential difference is established between said second electrode and each of said plurality of first electrodes, and wherein it is judged that there is a defect in at least one of said
10 plurality of insulators when said leakage current exceeds said predetermined value.

5. A method of insulator defect inspection comprising:
performing concurrent batch defect inspection of a
15 plurality of insulators which have respective apertures formed therein, by

disposing each of a plurality of first electrodes in an aperture of a corresponding one of said plurality of insulators, and disposing a second electrode such as to
20 enclose respective peripheries of said plurality of insulators, with said plurality of first electrodes, said plurality of insulators and said second electrode being enclosed within a pressure-proof chamber,

filling said pressure-proof chamber with air under a
25 pressure which is higher than atmospheric pressure,

establishing a potential difference between each of
said plurality of first electrodes and said second
electrodes, and measuring a level of leakage current which
flows between said plurality of first electrodes and said
5 second electrodes,

judging that there is a defect in at least one of said
plurality of insulators, when said leakage current exceeds
a first predetermined value, and

when it is found that there is a defect, performing an
10 individual unit sorting inspection of each of said
plurality of insulators by

disposing a first electrode in said aperture of said
each insulator, with a second electrode disposed to enclose
a periphery of said each insulator,

15 establishing a potential difference between said first
electrode and second electrode and measuring a level of
leakage current which flows between said first and second
electrodes, and

judging that there is a defect in said each insulator,
20 when said level of leakage current exceeds a second
predetermined value.

6. A method of insulator defect inspection according to
claim 5, comprising

upon completion of processing all of said plurality of insulators by said individual unit sorting inspection, selecting each of said plurality of insulators that have been found to be free from defect by said individual unit
5 sorting inspection, and applying said concurrent batch defect inspection to all of said selected insulators.

7. A method of insulator defect inspection according to claim 1, wherein said pressure-proof chamber is filled with
10 dry air under said high pressure, having a dew point which is lower than a predetermined value.